

IAP11 Rec'd PCT/PTO 16 AUG 2006

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No. : U.S. National Stage of PCT/EP2005/050639
Applicant : Dietmar Spanke et al.
Filed : 14 Feb. 2005
Title : Radiometric Measuring Device
Docket No. : SPAN3009/FJD
Customer No. : 23364

INFORMATION DISCLOSURE STATEMENT

COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. §1.51(b), §1.56, §1.97, and §1.98, this Information Disclosure Statement is submitted in the above-identified patent application. A listing of documents to be published on the face of any patent granted from this application is submitted herewith on Form PTO-1449. A copy of each document listed on form PTO-1449 is submitted herewith (with the exception of the U.S. references). A copy of the German and European Search Reports are also attached.

This Information Disclosure Statement is submitted within three months of the filing date of the above-identified U.S. Patent application.

The Examiner is requested to acknowledge consideration of the information provided in this paper in accordance with prescribed procedures.

Respectfully submitted,



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/Michael Logie/

05/16/2009

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /M.L./

B/O Form PTO-1449 U.S. Department of Commerce Patent and Trademark Office Information Disclosure Statement by Applicant	Atty. Docket Number SPAN30741-0000 Applicant Dietmar Spanke et al.	Serial Number JAP11 Rec'd PCI/PTO 16 AUG 2006 Group Unassigned
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U.S. Patent Documents

Foreign Patent Documents

Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)

		Von Dipl.-Ing. Alecsandru Nistor "Moderne Radiometrische Fullstandmesstechnik", XIP 000031866

Examiner	/Michael Logie/	Date Considered	05/16/2009
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EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.